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REVISION HISTORY

3/05—Rev. A to Rev. B

Updated Format.....	Universal
Changes to Specifications Tables.....	3
Changes to Figure 11.....	8
Updated Outline Dimensions	12
Changes to Ordering Guide	12

11/98—Rev. 0 to Rev. A

1/96—Revision 0: Initial Version

SPECIFICATIONS

DUAL SUPPLY¹

$V_{DD} = +15$ V, $V_{SS} = -15$ V, GND = 0 V, unless otherwise noted.

Table 1.

Parameter	+25°C	-40°C to +85°C	Unit	Test Conditions/ Comments
ANALOG SWITCH				
Analog Signal Range		V_{SS} to V_{DD}	V	
R_{ON}	12	25	Ω typ	$V_D = \pm 10$ V, $I_S = -1$ mA
ΔR_{ON}	1	3	Ω max	$V_D = -5$ V, 5 V, $I_S = -10$ mA
$R_{ONMatch}$	1	2.5	Ω typ	$V_D = \pm 10$ V, $I_S = -10$ mA
LEAKAGE CURRENTS				
Source OFF Leakage I_S (OFF)	± 0.005	± 5	nA typ	$V_{DD} = 16.5$ V, $V_{SS} = -16.5$ V
	± 0.25		nA max	$V_D = \pm 15.5$ V, $V_S = \pm 15.5$ V
Channel ON Leakage I_D , I_S (ON)	± 0.05	± 5	nA typ	Figure 13
	± 0.4		nA max	$V_S = V_D = \pm 15.5$ V
Figure 14				
DIGITAL INPUTS				
Input High Voltage, V_{INH}		2.4	V min	
Input Low Voltage, V_{INL}		0.8	V max	
Input Current, I_{INL} or I_{INH}		± 0.005	μA typ	
		± 0.5	μA max	$V_{IN} = 0$ V or V_{DD}
DYNAMIC CHARACTERISTICS ²				
t_{ON}	70	125	ns typ	$R_L = 300 \Omega$, $C_L = 35$ pF;
			ns max	$V_S = \pm 10$ V; Figure 15
t_{OFF}	60	120	ns typ	$R_L = 300 \Omega$, $C_L = 35$ pF;
			ns max	$V_S = \pm 10$ V; Figure 15
Break-Before-Make Delay, t_{OPEN}	10		ns min	$R_L = 300 \Omega$, $C_L = 35$ pF;
			pC typ	$V_S = +5$ V; Figure 16
Charge Injection	10			$V_D = 0$ V, $R_D = 0 \Omega$, $C_L = 10$ nF;
				Figure 17
OFF Isolation	72		dB typ	$R_L = 75 \Omega$, $C_L = 5$ pF, $f = 1$ MHz;
				$V_S = 2.3$ V rms, Figure 18
Channel-to-Channel Crosstalk	90		dB typ	$R_L = 75 \Omega$, $C_L = 5$ pF, $f = 1$ MHz;
				$V_S = 2.3$ V rms, Figure 19
C_S (OFF)	13		pF typ	
C_D, C_S (ON)	49		pF typ	
POWER REQUIREMENTS				
I_{DD}	0.05	0.35	mA typ	Digital inputs = 0 V or 5 V
			mA max	
I_{SS}	0.01		μA typ	
	1	5	μA max	
V_{DD}/V_{SS}		$\pm 3/\pm 20$	V min/V max	$ V_{DD} = V_{SS} $

¹ Temperature range is as follows: B version, -40°C to $+85^\circ\text{C}$.

² Guaranteed by design; not subject to production test.

ADG436

SINGLE SUPPLY¹

$V_{DD} = 12\text{ V}$, $V_{SS} = 0\text{ V}$, $GND = 0\text{ V}$, unless otherwise noted.

Table 2.

Parameter	+25°C	-40°C to +85°C	Unit	Test Conditions/ Comments
ANALOG SWITCH				
Analog Signal Range		0 to V_{DD}	V	
R_{ON}	20	40	Ω typ	$V_D = 1\text{ V}$, 10 V , $I_S = -1\text{ mA}$
$R_{ONMatch}$		2.5	Ω max Ω max	
LEAKAGE CURRENTS				
Source OFF Leakage I_S (OFF)	± 0.005		nA typ	$V_{DD} = 13.2\text{ V}$
	± 0.25	± 5	nA max	$V_D = 12.2\text{ V}$ / 1 V , $V_S = 1\text{ V}$ / 12.2 V
Channel ON Leakage I_D , I_S (ON)	± 0.05		nA typ	Figure 13
	± 4	± 5	nA max	$V_S = V_D = 12.2\text{ V}$ / 1 V
DIGITAL INPUTS				
Input High Voltage, V_{INH}		2.4	V min	
Input Low Voltage, V_{INL}		0.8	V max	
Input Current, I_{INL} or I_{INH}		± 0.005	μA typ	
		± 0.5	μA max	$V_{IN} = 0\text{ V}$ or V_{DD}
DYNAMIC CHARACTERISTICS ²				
t_{ON}	100	200	ns typ	$R_L = 300\text{ }\Omega$, $C_L = 35\text{ pF}$;
t_{OFF}	90	180	ns max	$V_S = 8\text{ V}$; Figure 15
Break-Before-Make Delay, t_{OPEN}	10		ns typ	$R_L = 300\text{ }\Omega$, $C_L = 35\text{ pF}$;
Charge Injection	10		pC typ	$V_S = 8\text{ V}$; Figure 15
OFF Isolation	72		dB typ	$R_L = 300\text{ }\Omega$, $C_L = 35\text{ pF}$;
Channel-to-Channel Crosstalk	90		dB typ	$V_S = 5\text{ V}$; Figure 16
C_S (OFF)	22		pF typ	$V_D = 6\text{ V}$, $R_D = 0\text{ }\Omega$, $C_L = 10\text{ nF}$; Figure 17
C_D , C_S (ON)	46		pF typ	$R_L = 75\text{ }\Omega$, $C_L = 5\text{ pF}$, $f = 1\text{ MHz}$;
				$V_S = 1.15\text{ V rms}$; Figure 18
				$R_L = 75\text{ }\Omega$, $C_L = 5\text{ pF}$, $f = 1\text{ MHz}$;
				$V_S = 1.15\text{ V rms}$, Figure 19
POWER REQUIREMENTS				
I_{DD}	0.05	0.35	mA typ	$V_{DD} = 13.5\text{ V}$
V_{DD}		+3/+30	mA max	Digital inputs = 0 V or 5 V
			V min/V max	

¹ Temperature range is as follows: B version, -40°C to $+85^\circ\text{C}$.

² Guaranteed by design; not subject to production test.

ABSOLUTE MAXIMUM RATINGS

T_A = 25°C unless otherwise noted.

Table 3.

Parameter	Rating
V _{DD} to V _{SS}	+44 V
V _{DD} to GND	-0.3 V to +30 V
V _{SS} to GND	+0.3 V to -30 V
Analog, Digital Inputs ¹	V _{SS} – 2 V to V _{DD} + 2V or 20 mA, whichever occurs first
Continuous Current, S or D	20 mA
Peak Current, S or D (pulsed at 1 ms, 10% Duty Cycle max)	40 mA
Operating Temperature Range	
Industrial (B Version)	-40°C to +85°C
Storage Temperature Range	-65°C to +125°C
Junction Temperature	150°C
θ _{JA} , Thermal Impedance	
PDIP Package	117°C/W
SOIC Package	77°C/W
Lead Temperature, Soldering (10 sec)	260°C
Lead Temperature, Soldering Vapor Phase (60 sec)	215°C
Infrared (15 sec)	220°C

¹ Overvoltages at IN, S, or D are clamped by internal diodes. Current should be limited to the maximum ratings given.

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Only one absolute maximum rating may be applied at any one time.

Table 4. Truth Table

Logic	Switch A	Switch B
0	Off	On
1	On	Off

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

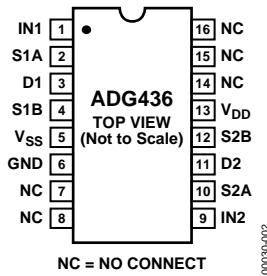


Figure 2. Pin Configuration

Table 5. Pin Function Descriptions

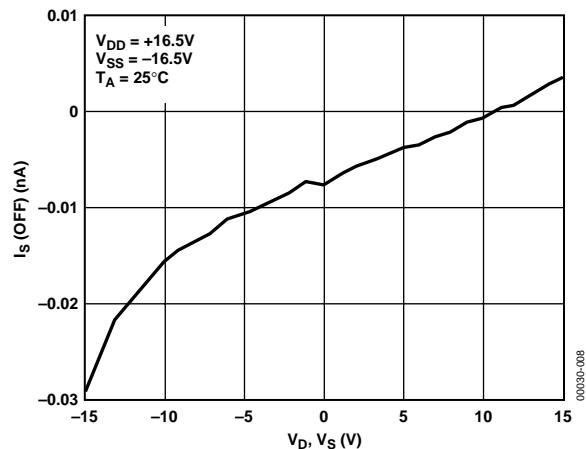
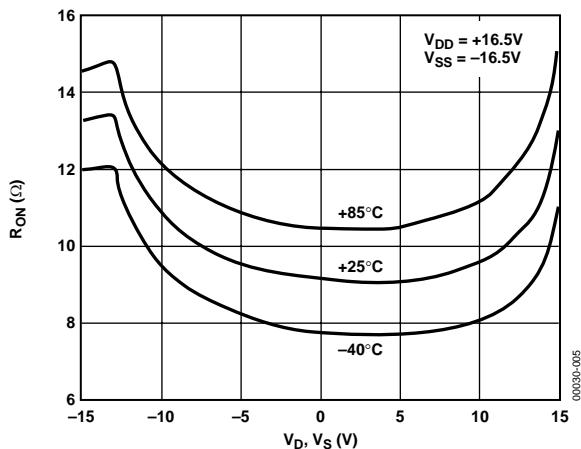
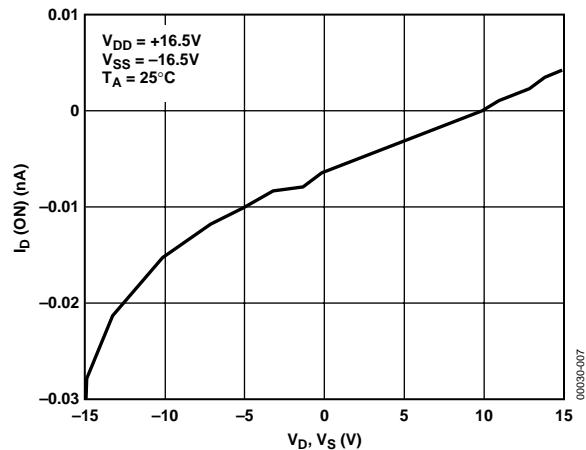
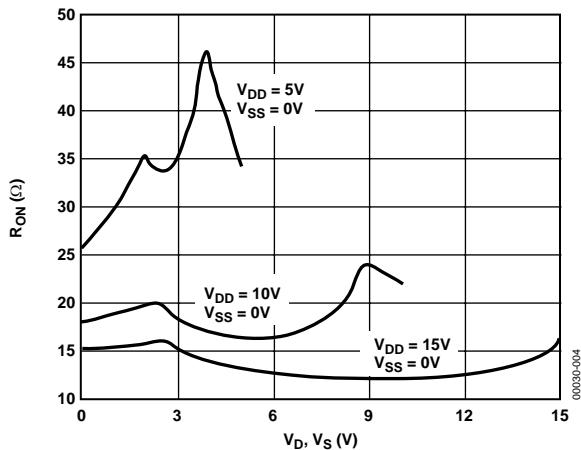
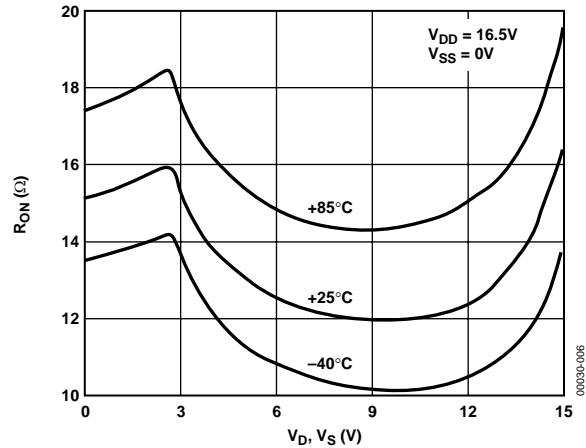
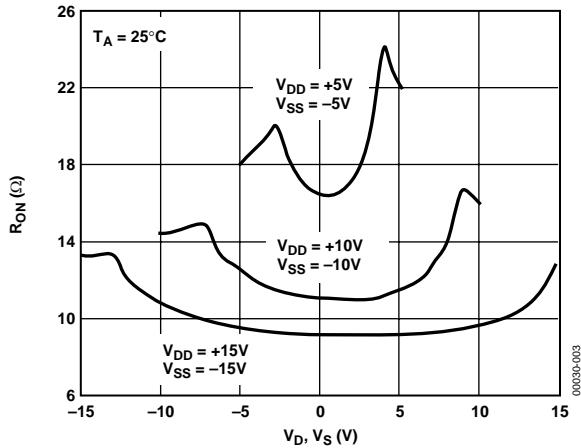
Pin No.	Mnemonic	Descriptions
1, 9	IN1, IN2	Logic Control Input.
2, 4, 10, 12	S1A, S1B, S2A, S2B	Source Terminal. Can be an input or output.
3, 11		Drain Terminal. Can be an input or output.
5	V _{SS}	Most Negative Power Supply Potential in Dual Supplies. In single-supply applications, it can be connected to ground.
6	GND	Ground (0 V) Reference.
7, 8, 14, 15, 16	NC	No Connect.
13	V _{DD}	Most Positive Power Supply Potential.

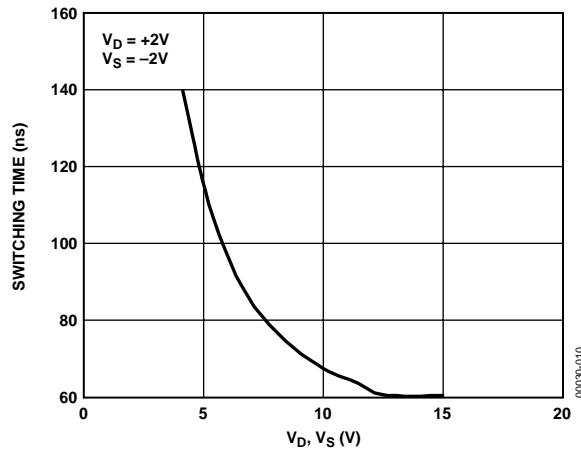
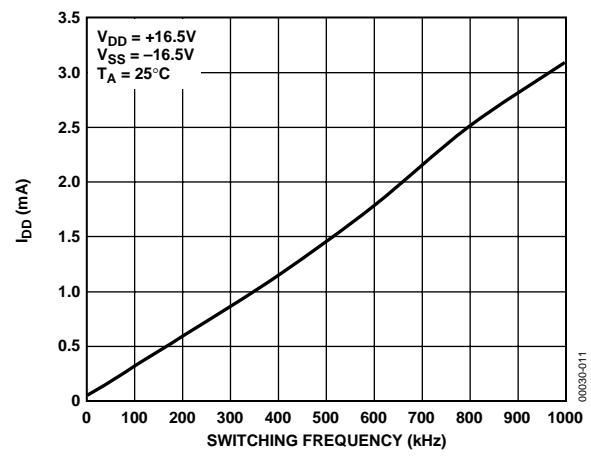
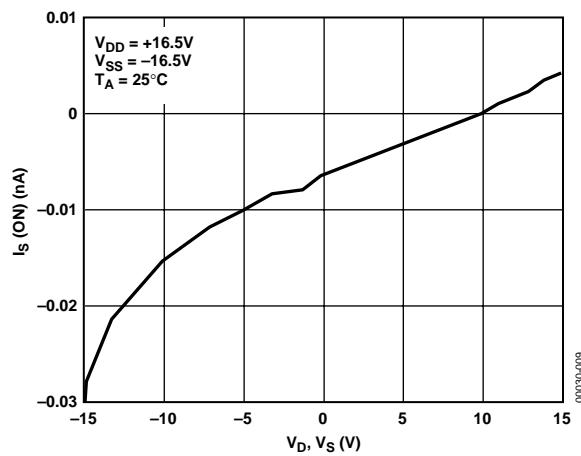
TERMINOLOGY

Table 6.

Mnemonic	Descriptions
R _{ON}	Ohmic resistance between D and S.
ΔR _{ON}	R _{ON} variation due to a change in the analog input voltage with a constant load current.
R _{ONMatch}	Difference between the R _{ON} of any two channels.
I _S (OFF)	Source leakage current with the switch off.
I _D , I _S (ON)	Channel leakage current with the switch on.
V _D (V _S)	Analog voltage on terminals D, S.
C _S (OFF)	OFF switch source capacitance.
C _D , C _S (ON)	ON switch capacitance.
t _{ON}	Delay between applying the digital control input and the output switching on.
t _{OFF}	Delay between applying the digital control input and the output switching off.
t _{OPEN}	Break-before-make delay when switches are configured as a multiplexer.
V _{INL}	Maximum input voltage for Logic 0.
V _{INH}	Minimum input voltage for Logic 1.
I _{INL} (I _{INH})	Input current of the digital input.
Crosstalk	A measure of unwanted signal that is coupled through from one channel to another as a result of parasitic capacitance.
Off Isolation	A measure of unwanted signal coupling through an OFF switch.
Charge Injection	A measure of the glitch impulse transferred from the digital input to the analog output during switching.
I _{DD}	Positive supply current.
I _{SS}	Negative supply current.

TYPICAL PERFORMANCE CHARACTERISTICS





TEST CIRCUITS

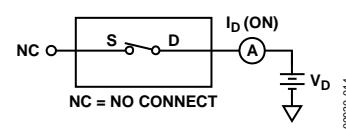
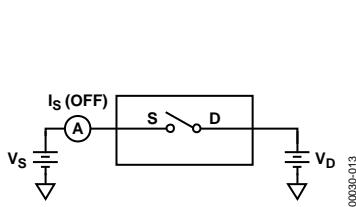
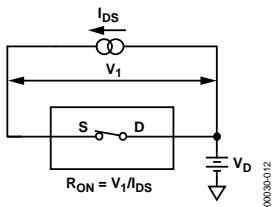


Figure 12. On Resistance

Figure 13. Off Leakage

Figure 14. On Leakage

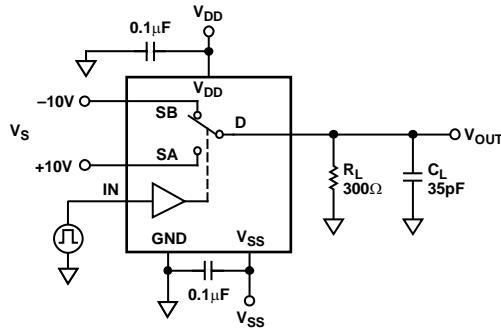


Figure 15. Switching Times

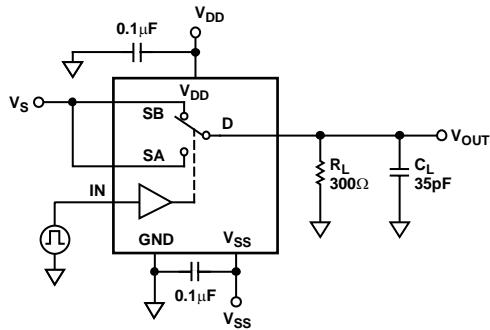
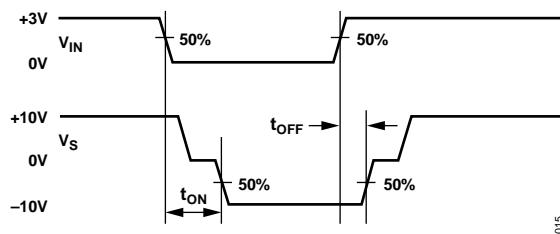
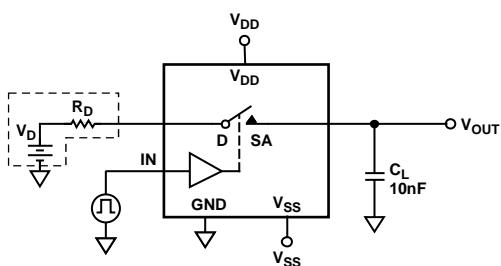
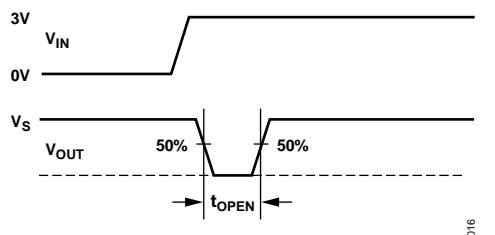
Figure 16. Break-Before-Make Delay, t_{open} 

Figure 17. Charge Injection

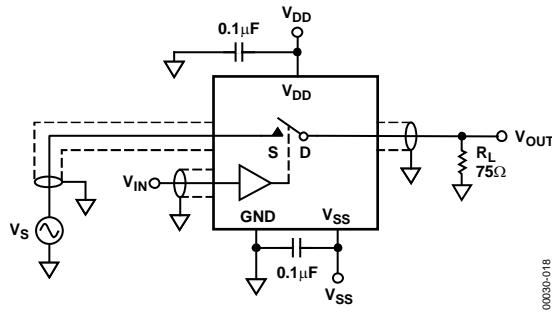
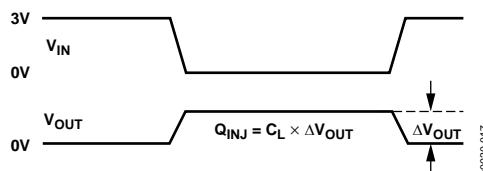


Figure 18. Off Isolation

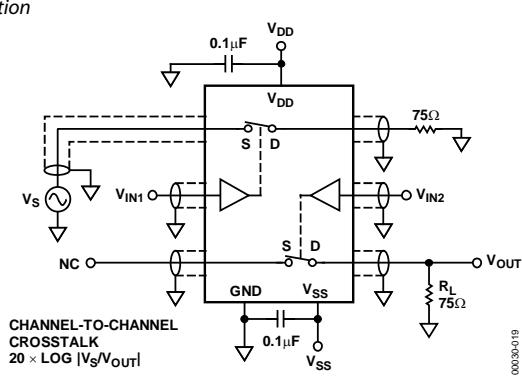


Figure 19. Channel-to Channel Crosstalk

APPLICATIONS INFORMATION

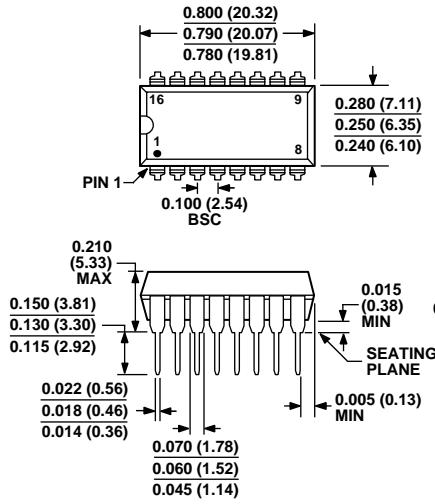
ADG436 SUPPLY VOLTAGES

The ADG436 can operate from a dual or single supply. V_{SS} should be connected to GND when operating with a single supply. When using a dual supply, the ADG436 can also operate with unbalanced supplies, for example $V_{DD} = 20\text{ V}$ and $V_{SS} = -5\text{ V}$. The only restrictions are that V_{DD} to GND must not exceed 30 V, V_{SS} to GND must not drop below -30 V, and V_{DD} to V_{SS} must not exceed +44 V. It is important to remember that the ADG436 supply voltage directly affects the input signal range, the switch on resistance and the switching times of the part. The effects of the power supplies on these characteristics can be clearly seen from the Typical Performance Characteristics curves.

POWER-SUPPLY SEQUENCING

When using CMOS devices, care must be taken to ensure correct power-supply sequencing. Incorrect power-supply sequencing can result in the device being subjected to stresses beyond those listed in the Absolute Maximum Ratings. Always sequence V_{DD} on first followed by V_{SS} and the logic signals. An external signal can then be safely presented to the source or drain of the switch.

OUTLINE DIMENSIONS

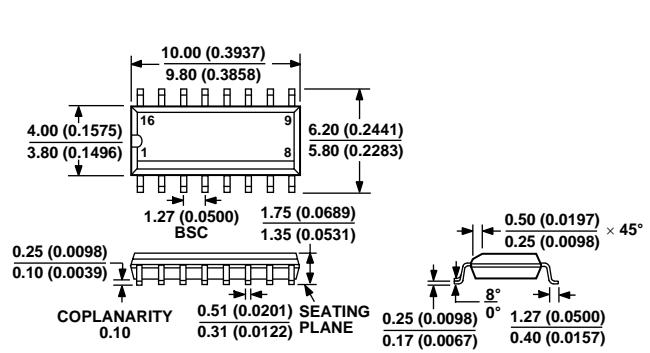


COMPLIANT TO JEDEC STANDARDS MS-001-AB

CONTROLLING DIMENSIONS ARE IN INCHES; MILLIMETER DIMENSIONS
(IN PARENTHESES) ARE ROUNDED-OFF INCH EQUIVALENTS FOR
REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN.
CORNER LEADS MAY BE CONFIGURED AS WHOLE OR HALF LEADS.

Figure 20. 16-Lead Plastic Dual In-Line Package [PDIP]
(N-16)

Dimensions are shown in inches and (millimeters)



COMPLIANT TO JEDEC STANDARDS MS-012-AC

CONTROLLING DIMENSIONS ARE IN MILLIMETERS; INCH DIMENSIONS
(IN PARENTHESES) ARE ROUNDED-OFF MILLIMETER EQUIVALENTS FOR
REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN

Figure 21. 16-Lead Narrow Body Standard Small Outline Package [SOIC]
(R-16)

Dimensions are shown in millimeters and (inches)

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option
ADG436BN	-40°C to +85°C	16-Lead PDIP	N-16
ADG436BNZ ¹	-40°C to +85°C	16-Lead PDIP	N-16
ADG436BR	-40°C to +85°C	16-Lead 0.15" Narrow Body SOIC	R-16
ADG436BR-REEL	-40°C to +85°C	16-Lead 0.15" Narrow Body SOIC	R-16
ADG436BRZ	-40°C to +85°C	16-Lead 0.15" Narrow Body SOIC	R-16
ADG436BRZ-REEL	-40°C to +85°C	16-Lead 0.15" Narrow Body SOIC	R-16

¹ Z = Pb-free part.